

Figures

credits for all figures: P. Thibault/ F. Pfeiffer (PSI/ EPFL)

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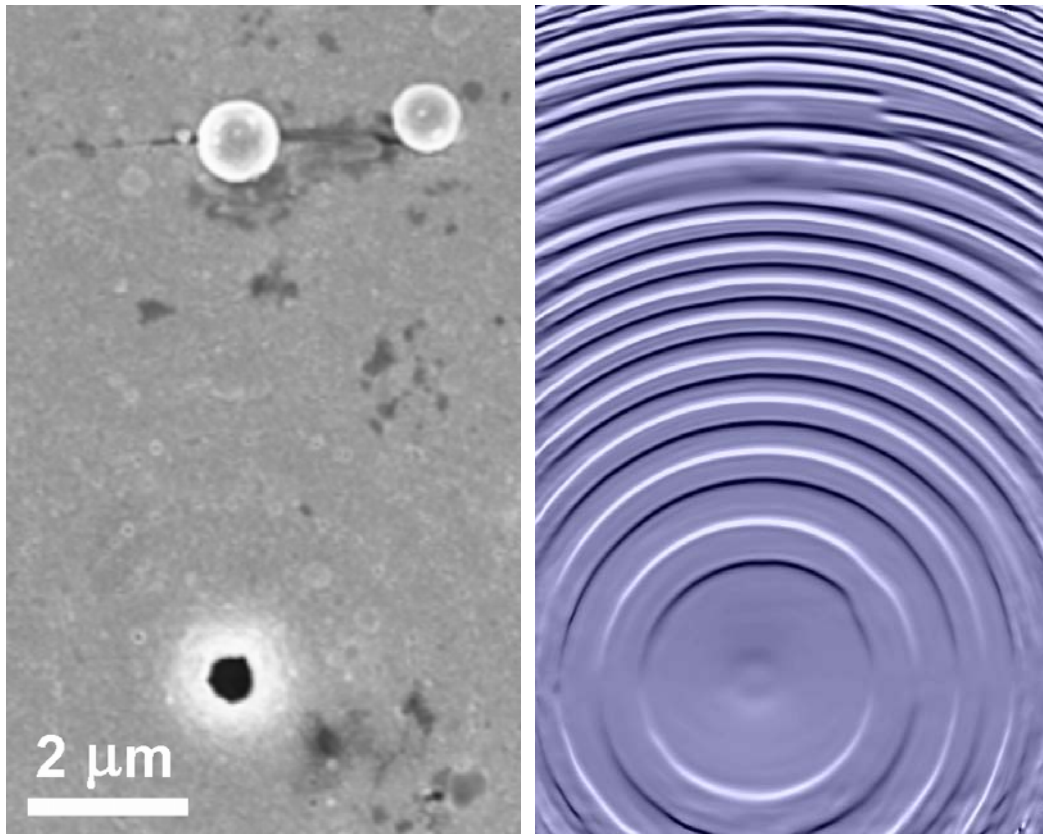


Fig. 1| Left panel: Conventional Scanning Electron Micrograph (SEM) image of the sample. Right panel: The novel super-resolution X-ray microscopy method visualizes details and line defects in the buried nanostructure.

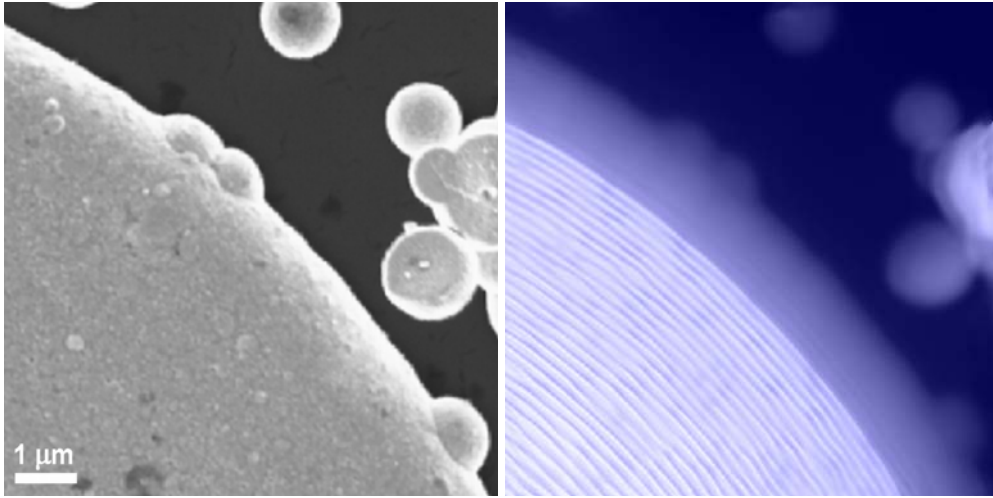


Fig. 2| Left panel: Conventional Scanning Electron Micrograph (SEM) image of the sample. Right panel: The novel super-resolution X-ray microscopy method visualizes details and line defects in the buried nanostructure.

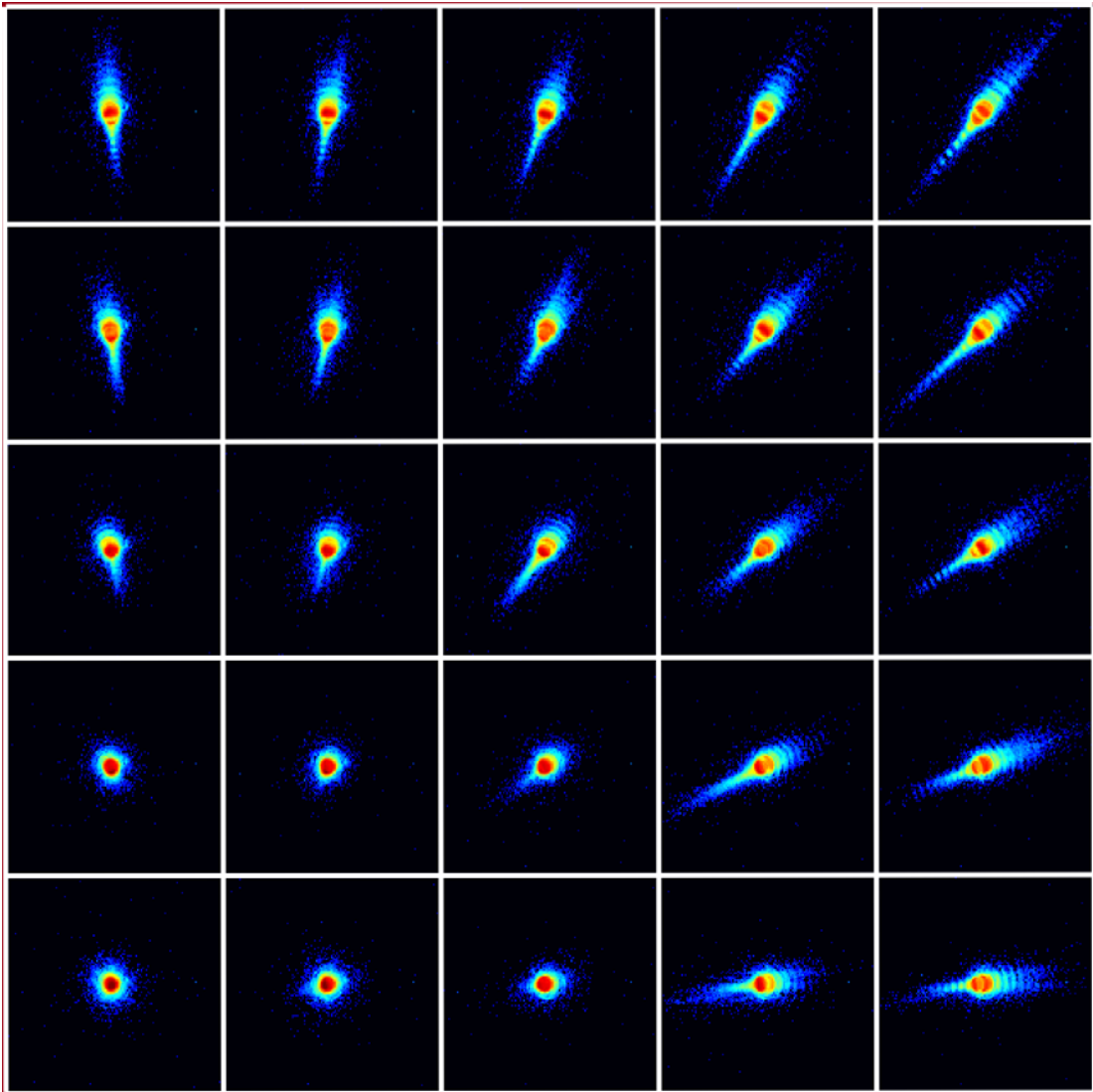


Fig. 3| Twenty-five out of typically ten-thousand coherent x-ray diffraction images used for reconstructing one single super-resolution x-ray micrograph.